- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

### description

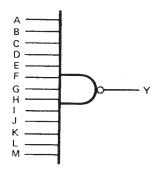
These devices contain a single 13-input NAND gate.

The SN54133 is characterized for operation over the full military temperature range of  $-55\,^{\circ}\text{C}$  to 125 $^{\circ}\text{C}$ . The SN74133 is characterized for operation from 0 $^{\circ}\text{C}$  to 70 $^{\circ}\text{C}$ .

#### **FUNCTION TABLE**

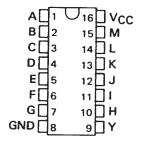
INPUTS A THRU M	ОПТРИТ У
All inputs H One or more inputs L	L
and an inord inputs E	"

#### logic diagram

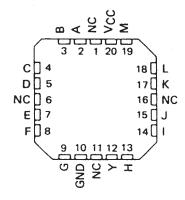


### positive logic

SN54S133 . . . J OR W PACKAGE SN74S133 . . . D OR N PACKAGE (TOP VIEW)

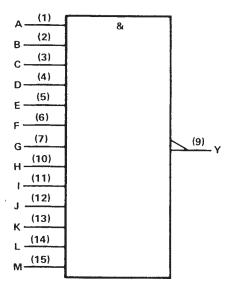


# SN54S133 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

### logic symbol†

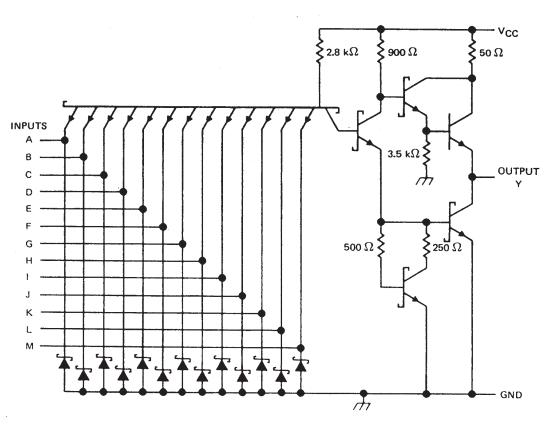


<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.



**'S133** 



Resistor values shown are nominal.

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range: SN54'	- 55°C to 125°C
SN74'	0° C to 70° C
Storage temperature range	- 65° C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal.



## recommended operating conditions

			SN54S133			SN74S133		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			8.0	v
ЮН	High-level output current			<b>– 1</b>			- 1	mA
loL	Low-level output current			20			20	mA
TA	Operating free-air temperature	- 55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †			SN54S133			SN74S133			
	TEST CONDITIONS I			MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V <sub>CC</sub> = MIN,	I <sub>I</sub> = -18 mA				-1.2			-1.2	٧
V <sub>ОН</sub>	V <sub>CC</sub> = MIN,	V <sub>IL</sub> = 0.8 V,	I <sub>OH</sub> = -1 mA	2.5	3.4		2.7	3.4		V
VOL	V <sub>CC</sub> = MIN,	V <sub>IH</sub> = 2 V,	IOL = 20 mA			0.5			0.5	V
11	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 5.5 V				1			1	mA
11Н	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.7 V				50			50	μА
lı L	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0.5 V				-2			-2	mA
I <sub>OS</sub> §	V <sub>CC</sub> = MAX			40		-100	-40		-100	mA
<sup>1</sup> ССН	V <sub>CC</sub> = MAX,	VI = 0 V			3	5		3	5	mA
ICCL	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 4.5 V			5.5	10		5.5	10	mA

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN TYP	MAX	UNIT
<sup>t</sup> PLH			P 390 O	0 45 5	4	6	ns
<sup>t</sup> PHL	Any	Y	$R_L = 280 \Omega$ ,	C <sub>L</sub> = 15 pF	4.5	7	ns
<sup>t</sup> PLH			R <sub>L</sub> = 280 Ω,	C <sub>L</sub> = 50 pF	5.5		ns
<sup>t</sup> PHL					6.5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ . § Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

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